

**METHOD OF DEFECT CONTROL**

Appl. No. : 10/708,783 Confirmation No. 2782  
Applicant : Long-Hui Lin  
Filed : March 25, 2004  
TC/A.U. : 2863  
Examiner : Xiuqin Sun  
Docket No. : LKSP0026USA0  
Customer : 27765  
No. :

Commissioner for Patents  
P.O. Box 1450  
Alexandria VA 22313-1450

**AMENDMENT**

Sir:

- 5 In response to the Office action of April 18, 2005, please amend the above-identified application as follows:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 4 of this paper.